

# Search Notes



Application/Control No.

10/523,049

Examiner

Lan Nguyen

Applicant(s)/Patent under Reexamination

FUKUZAWA ET AL.

Art Unit

3683

## SEARCHED

Class	Subclass	Date	Examiner
188	290		
	296	✓ 12/14/06	XLN
	293		
16	49		
	51		
	53		
	54	X ↓	↓

## INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

## SEARCH NOTES (INCLUDING SEARCH STRATEGY)

	DATE	EXMR
TEXT SEARCH included	12/14/06	XLN